

BS EN 62417:2010



BSI Standards Publication

Semiconductor devices — Mobile ion tests for metal-oxide semiconductor field effect transistors (MOSFETs)

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The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Amendments issued since publication

Amd. No.	Date	Text affected
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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 62417

May 2010

ICS 31.080

English version

**Semiconductor devices -
Mobile ion tests for metal-oxide semiconductor field effect transistors
(MOSFETs)
(IEC 62417:2010)**

Dispositifs à semiconducteurs -
Essais d'ions mobiles pour transistors
à semiconducteur à oxyde métallique
à effet de champ (MOSFET)
(CEI 62417:2010)

Halbleiterbauelemente -
Prüfverfahren auf mobile Ionen
für Feldeffekttransistoren mit Metall-Oxid-
Halbleiter (MOSFET)
(IEC 62417:2010)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 47/2042/FDIS, future edition 1 of IEC 62417, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62417 on 2010-05-01.

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The following dates were fixed:

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| – latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement | (dop) | 2011-02-01 |
| – latest date by which the national standards conflicting with the EN have to be withdrawn | (dow) | 2013-05-01 |

Endorsement notice

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